

TOSHIBA Field Effect Transistor Silicon P-Channel MOS Type

# SSM3J112TU

High Speed Switching Applications

- 4V drive
- Low on-resistance:  $R_{on} = 790\text{m}\Omega$  (max) (@ $V_{GS} = -4\text{ V}$ )  
 $R_{on} = 390\text{m}\Omega$  (max) (@ $V_{GS} = -10\text{ V}$ )

## Absolute Maximum Ratings (Ta = 25°C)

| Characteristic            | Symbol         | Rating   | Unit |
|---------------------------|----------------|----------|------|
| Drain-Source voltage      | $V_{DS}$       | -30      | V    |
| Gate-Source voltage       | $V_{GSS}$      | $\pm 20$ | V    |
| Drain current             | DC             | $I_D$    | -1.1 |
|                           | Pulse          | $I_{DP}$ | -2.2 |
| Drain power dissipation   | $P_D$ (Note 1) | 800      | mW   |
|                           | $P_D$ (Note 2) | 500      |      |
| Channel temperature       | $T_{ch}$       | 150      | °C   |
| Storage temperature range | $T_{stg}$      | -55~150  | °C   |

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

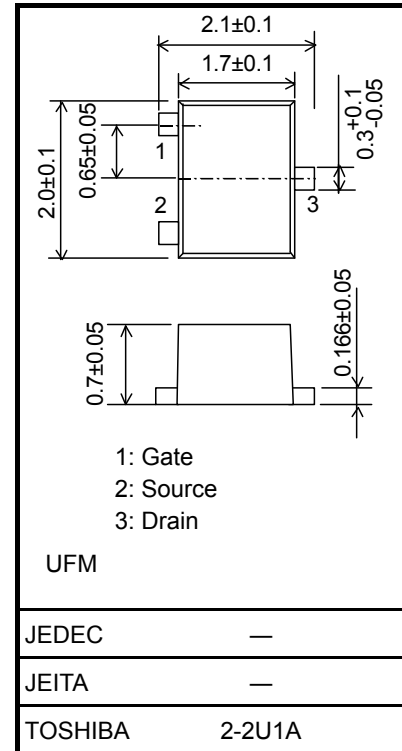
- Note 1: Mounted on ceramic board.  
 (25.4 mm × 25.4 mm × 0.8 mm, Cu Pad: 645 mm<sup>2</sup>)
- Note 2: Mounted on FR4 board.  
 (25.4 mm × 25.4 mm × 1.6 mm, Cu Pad: 645 mm<sup>2</sup>)

## Electrical Characteristics (Ta = 25°C)

| Characteristic                 | Symbol         | Test Conditions  | Min  | Typ. | Max     | Unit |
|--------------------------------|----------------|--|------|------|---------|------|
| Drain-Source breakdown voltage | $V_{(BR) DSS}$ | $I_D = -1\text{ mA}, V_{GS} = 0$   | -30  | —    | —       | V    |
|                                | $V_{(BR) DSX}$ | $I_D = -1\text{ mA}, V_{GS} = +20\text{ V}$  | -15  | —    | —       |      |
| Drain cut-off current          | $I_{DSS}$      | $V_{DS} = -30\text{ V}, V_{GS} = 0$  | —    | —    | -1      | μA   |
| Gate leakage current           | $I_{GSS}$      | $V_{GS} = \pm 16\text{ V}, V_{DS} = 0$   | —    | —    | $\pm 1$ | μA   |
| Gate threshold voltage         | $V_{th}$       | $V_{DS} = -5\text{ V}, I_D = -0.1\text{ mA}$   | -0.8 | —    | -1.8    | V    |
| Forward transfer admittance    | $ Y_{fs} $     | $V_{DS} = -5\text{ V}, I_D = -0.5\text{ A}$ (Note3)  | 0.5  | 1.0  | —       | S    |
| Drain-Source on-resistance     | $R_{DS(ON)}$   | $I_D = -0.5\text{ A}, V_{GS} = -10\text{ V}$ (Note3)   | —    | 310  | 390     | mΩ   |
|                                |                | $I_D = -0.5\text{ A}, V_{GS} = -4\text{ V}$ (Note3)  | —    | 610  | 790     |      |
| Input capacitance              | $C_{iss}$      | $V_{DS} = -15\text{ V}, V_{GS} = 0, f = 1\text{ MHz}$  | —    | 86   | —       | pF   |
| Output capacitance             | $C_{oss}$      | $V_{DS} = -15\text{ V}, V_{GS} = 0, f = 1\text{ MHz}$  | —    | 25   | —       | pF   |
| Reverse transfer capacitance   | $C_{rss}$      | $V_{DS} = -15\text{ V}, V_{GS} = 0, f = 1\text{ MHz}$  | —    | 14   | —       | pF   |
| Switching time                 | Turn-on time   | $V_{DD} = -15\text{ V}, I_D = -0.5\text{ A},$<br>$V_{GS} = 0 \sim -4\text{ V}, R_G = 10\ \Omega$ | —    | 14   | —       | ns   |
|                                | Turn-off time  |  | —    | 8.5  | —       |      |
| Drain-Source forward voltage   | $V_{DSF}$      | $I_D = 1.1\text{ A}, V_{GS} = 0\text{ V}$ (Note3)  | —    | 0.85 | 1.2     | V    |

Note3: Pulse test

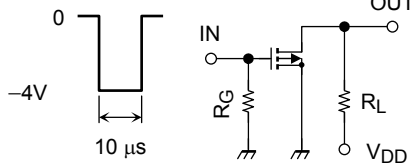
Unit: mm



Weight: 6.6 mg (typ.)

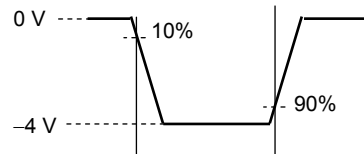
## Switching Time Test Circuit

### (a) Test circuit

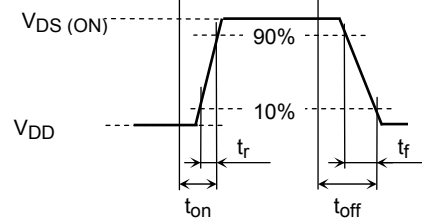


$V_{DD} = -10\text{ V}$   
 $R_G = 4.7\ \Omega$   
 $D.U. \leq 1\%$   
 $V_{IN}: t_r, t_f < 5\text{ ns}$   
 Common Source  
 $T_a = 25^\circ\text{C}$

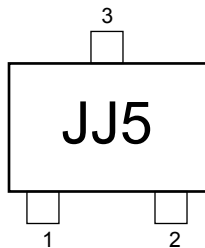
### (b) $V_{IN}$



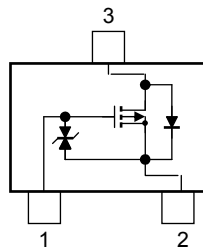
### (c) $V_{OUT}$



## Marking



## Equivalent Circuit (top view)



## Precaution

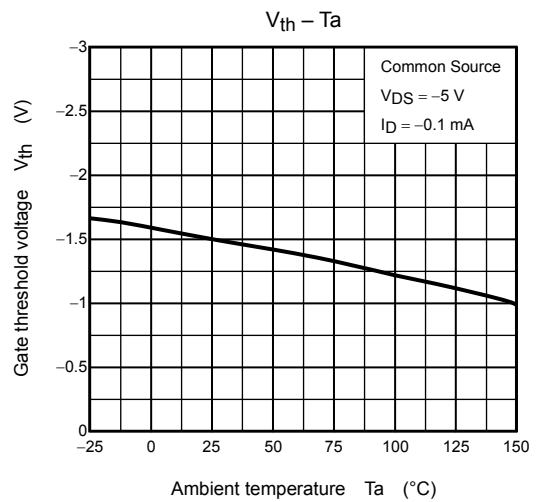
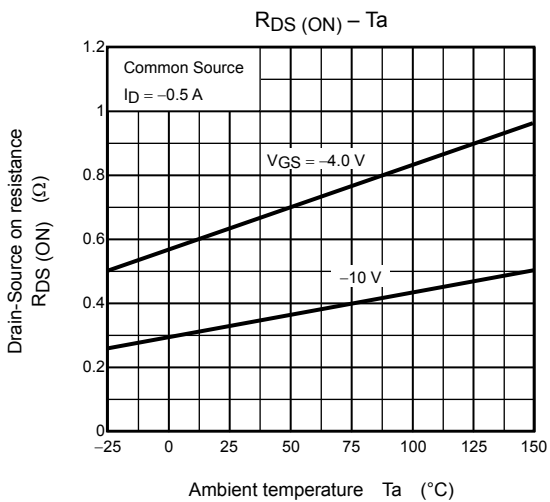
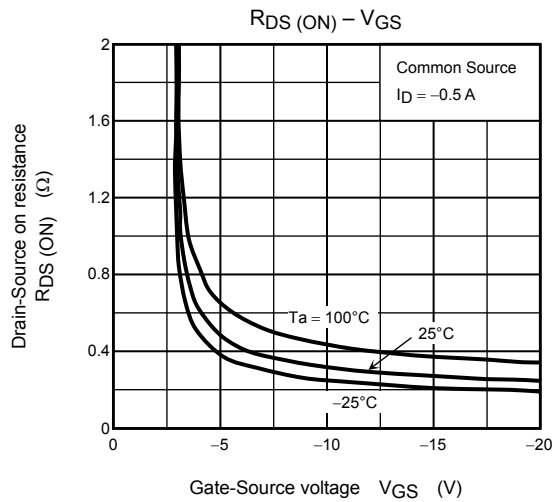
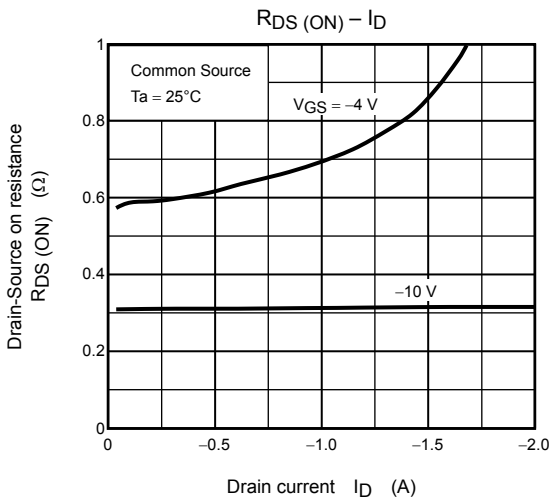
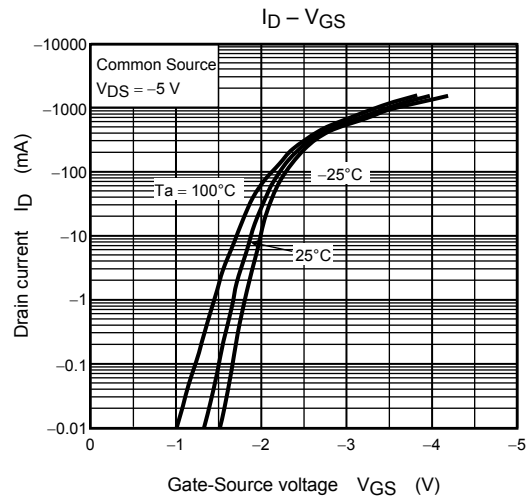
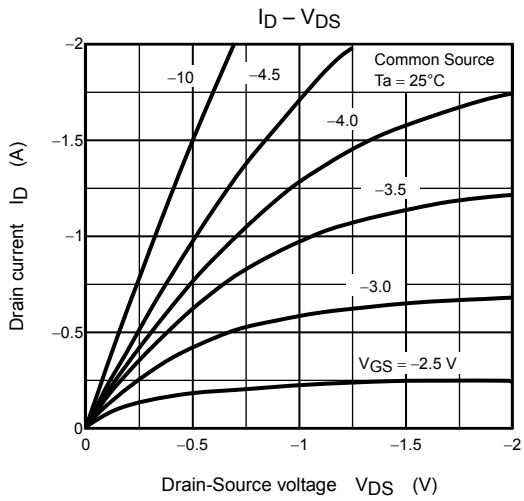
$V_{th}$  can be expressed as the voltage between gate and source when the low operating current value is  $I_D = -0.1\text{ mA}$  for this product. For normal switching operation,  $V_{GS(ON)}$  requires a higher voltage than  $V_{th}$ , and  $V_{GS(OFF)}$  requires a lower voltage than  $V_{th}$ .

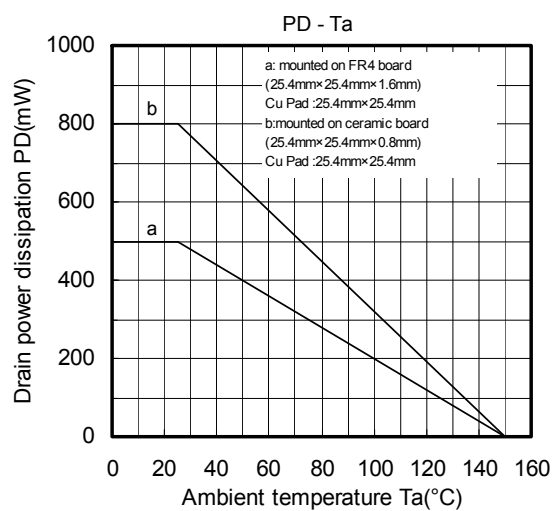
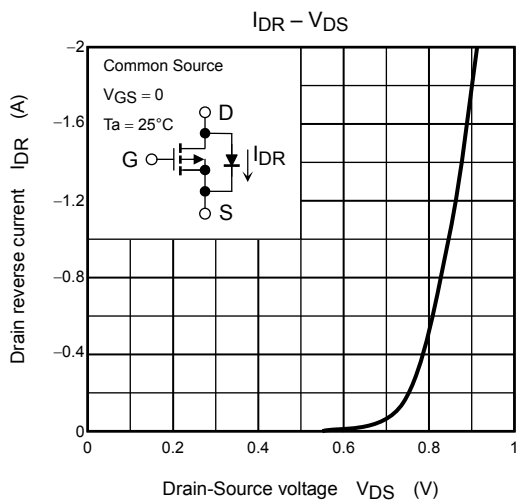
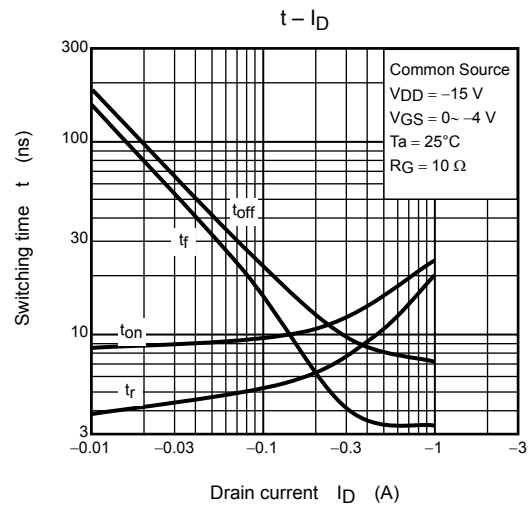
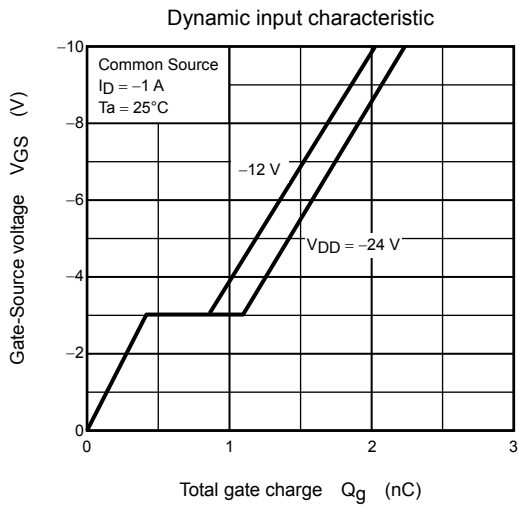
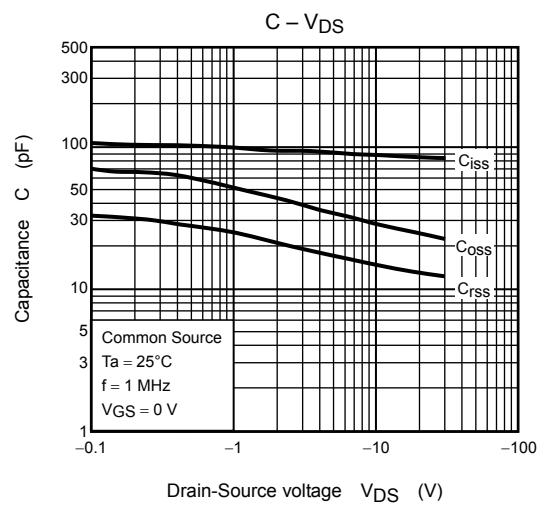
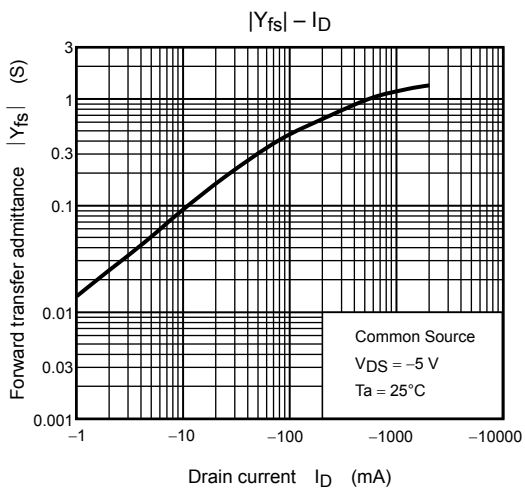
(The relationship can be established as follows:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ )

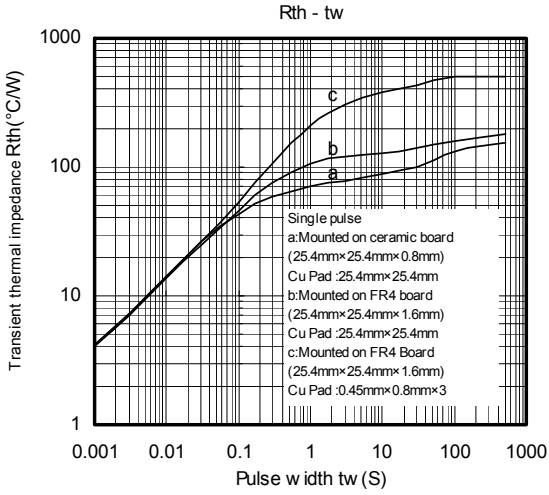
Take this into consideration when using the device.

## Handling Precaution

When handling individual devices which are not yet mounted on a circuit board, be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.







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20070701-EN GENERAL

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